

Correction to “Insights into π -Conjugated Small Molecule Neat Films and Blends As Determined Through Photoconductivity”

[ACS Nano 2012, 6, 8735–8745. DOI: 10.1021/nn303724m]. Jacek J. Jasieniak, Ben B.Y. Hsu, Christopher J. Takacs, Gregory C. Welch, Guillermo C. Bazan, Daniel Moses, and Alan J. Heeger*

Page 8737. Figure 2 in our article was incorrectly reproduced. The correct figure appears below.

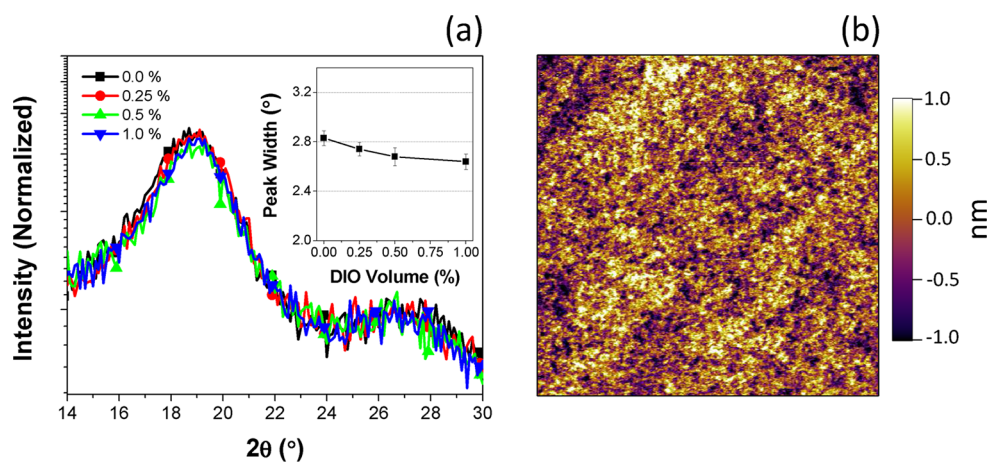


Figure 2. (a) Out-of-plane X-ray diffraction of PC₇₁BM thin-films as a function of DIO concentration in the deposition solution. (Inset) Gaussian peak width of the $2\theta \approx 18.9^\circ$ ($d \approx 0.47$ nm) scattering contribution depicting changes to the long-range out-of-plane ordering in the sample. (b) A $4 \mu\text{m}^2$ AFM micrograph of the 0% DIO PC₇₁BM sample. The corresponding RMS roughness of the sample is 0.51 nm.

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